

Specification

Physical and chemical properties

PCP
RD 50™

RD 50™

Radiation shielding glass RD 50™ protects against X-rays and gamma rays in the medical and technical field. In research works it also provides necessary safety screening.

RD 50™ is an extra dense flint glass. Its protective effect is based on its high content of heavy metallic oxides of nearly 70 per cent by weight. The lead oxide content alone is more than 65 per cent by weight. Therefore, a density of above 5.05 g/cm³ is reached, so that relatively small thicknesses fulfil all legal safety regulations. Radiation shielding glass RD 50™ meets the requirements of DIN EN 61331-2. The protective capacity of a radiation shielding glass for X-rays is indicated by the attenuation equivalent, either in relation of lead thickness to glass thickness in per cent or in mm Pb.

The subsequent properties are based primarily upon the measuring results of the very latest standards and measuring methods, which are defined in corresponding "Measuring and Test Procedures".

We retain the right to change the data in keeping with the latest technical standards.

Non-toleranced numerical values are reference values of an average production quality.

Values marked with \diamond do not apply to the type of glass or no values are available.

Requirements deviating from these specifications must be defined in writing in a **customer agreement**.

Specification		PCP RD 50™	
Physical and chemical properties			
1.	Optical properties		
1.1	Refractive index	n_D	1.79
1.2	Transmittance data		
1.2.1	Spectral transmittance $\tau(\lambda)$		
1.2.1.1	$\tau(\lambda)$ - curve		
	Plot of spectral transmittance $\tau(\lambda)$ for $d = 5.0$ mm, $d = 10.0$ mm, $d = 20.0$ mm ($\lambda = 340$ nm to 800 nm)	see annex	
1.2.1.2	$\tau(\lambda)$ - individual values in % ($d = 10$ mm)		
	τ at $\lambda = 550$ nm	τ_{550}	85
1.2.1.3	Edge wavelength ($d = 5.0$ mm)		
	Edge wavelength λ_c ($\tau = 0.46$) in nm	397	
1.2.2	Luminous transmittance τ_v as a function of thickness		
		Thickness in mm	τ_{vD65} in %
			τ_{vA} in %
		5.0	85
		10.0	84
		20.0	82.5
			83
2.	Thermal properties		
2.1	Viscosities and corresponding temperatures		
	Designation	Viscosity $\lg \eta$ in dPas	Temperature ϑ in °C
	Strain point	14.5	444
	Annealing point	13.0	467
	Softening point	7.6	603
	Forming temperature	6.0	673
	Forming temperature	5.0	729
	Forming temperature	4.0	800
2.2	Transformation temperature T_g in °C	467	
2.3	Coefficient of thermal expansion α		
2.3.1	Coefficient of mean linear thermal expansion		
	$\alpha(20$ °C; 300 °C) in 10^{-6} K^{-1} (Static measurement)	7.4	
2.4		disregard	
2.5	Mean specific heat capacity $c_p(20$ °C to 100 °C) in J/(g · K)	0.39	
2.6	Thermal conductivity λ in W/ (m·K) for 50 °C	0.62	

VX 0050/1e

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Physical and chemical properties		
3.	Mechanical properties	
3.1	Density ρ in g/cm ³ (Condition as supplied)	≥ 5.05
3.2	Stress optical coefficient C in $1.02 \cdot 10^{-12}$ m ² /N	0.78
3.3	Breaking strength	disregard
3.4	Young's modulus E in kN/mm ²	56.6
3.5	Poisson's ratio μ	0.245
3.6	Torsion modulus G in kN/mm ²	22.7
3.7	Knoop hardness HK 0.1/20	360
4.	Chemical properties	
4.1	Hydrolytic resistance acc. to DIN ISO 719	
	Hydrolytic class	HGB 1
	Equivalent of alkali (Na ₂ O) per gram of glass grains in µg/g	24
4.2	Acid resistance acc. to DIN 12 116	
	Acid class	◇
	Half surface weight loss after 6 hours in mg/dm ²	◇
4.3	Alkali resistance acc. to DIN ISO 695	
	Class	A 3
	Surface weight loss after 3 hours in mg/dm ²	510
5.	Electrical properties	disregard

VX 0050/1e

Specification		PCP RD 50™
Physical and chemical properties		
6.	Other properties	
6.1	Attenuation equivalent for lead in % of glass thickness for different types of radiation	
6.1.1	X - radiation quality	
6.1.1.1	Nominal thickness 0.65 cm (5 mm to 6.5 mm),	
	Nominal thickness 0.75 cm (6 mm to 7.5 mm)	
	Tube voltage 80 kV/0.16 mm Cu total filtering	30.1
	Tube voltage 90 kV*/0.20 mm Cu total filtering	30.7
	Tube voltage 100 kV/0.25 mm Cu total filtering	30.5
	Tube voltage 110 kV*/0.40 mm Cu total filtering	30.5
	Tube voltage 150 kV/0.70 mm Cu total filtering	30.1
	Tube voltage 200 kV/1.20 mm Cu total filtering	28.6
6.1.1.2	Nominal thickness 0.85 cm (7 mm to 8.5 mm)	
	Tube voltage 80 kV/0.16 mm Cu total filtering	29.2
	Tube voltage 90 kV*/0.20 mm Cu total filtering	29.3
	Tube voltage 100 kV/0.25 mm Cu total filtering	30.2
	Tube voltage 110 kV*/0.40 mm Cu total filtering	30.9
	Tube voltage 150 kV/0.70 mm Cu total filtering	30.2
	Tube voltage 200 kV/1.20 mm Cu total filtering	28.8
6.1.1.3	Nominal thickness ≥ 1.0 cm (> 8.5 mm)	
	Tube voltage 90 kV*/0.20 mm Cu total filtering	29.9
	Tube voltage 100 kV/0.25 mm Cu total filtering	30.0
	Tube voltage 110 kV*/0.40 mm Cu total filtering	30.0
	Tube voltage 150 kV/0.70 mm Cu total filtering	30.1
	Tube voltage 200 kV/1.20 mm Cu total filtering	28.9
<p>*Tube voltage not enclosed in DIN EN 61331-1 For tube voltages > 200 kV the attenuation equivalent for 200 kV should be taken as basis</p>		
<p>Measuring and Test Procedures (TÜV NORD RÖNTGENTECHNIK TÜV Hannover / Sachsen-Anhalt e.V.)</p>		
<p>General The tests were performed at the technical center of TÜV Hannover/Sachsen Anhalt e. V., as well as the radiology clinic of the Henriettenstiftung Hannover, using the STABILIPAN therapeutic unit from Siemens.</p>		

VX 0050/1e

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Physical and chemical properties		
<p>Test Setup</p> <p>The test setup took place in accordance with DIN 6845 T1 taking into consideration the geometries for measurements within a narrow beam of rays. Specimens with the dimensions 120 mm x 120 mm were aligned inside an erected channel formed using lead bricks so that they could be irradiated on a surface of 50 cm² in the middle of the sample. The aperture with the apparatus for insertion of the Cu filter was positioned near the focal point and at the end of the measuring channel in the middle of the central beam to achieve the radiation quality required by the DIN standard. To minimize radiation scattering that can be expected as a result of the high energy, the area between the ray exit window and the aperture was shielded with an additional 1.0 mm of lead.</p> <p>Used measuring devices</p> <ul style="list-style-type: none"> · Dosimeter Diados QS-No.: 400152 · Lead foil QS-No.: 400151 · Monitor Dosimeter QS-No.: 400037 · Radiator MCN 165 QS-No.: 420505 · Cu Filter QS-No.: 400216 <p>Attenuation equivalent in mm Pb</p> <p>To determine the attenuation equivalents, the specimen was comparatively measured using lead foil with various thicknesses. The attenuation equivalent was determined through linear interpolation from the measured dose rates behind two lead foils with varying thicknesses and the specimen.</p>		
6.1.2	Gamma radiation	
6.1.2.1	Tests PTB	
	⁶⁰ Co ¹³⁷ Cs ¹³¹ I ¹⁹² Ir	38.3 35.8 33.6 28.2
<p>Measuring and Test Procedures (PTB Braunschweig)</p> <p>For X-radiation (constant voltage) the lead equivalent is defined by the radiation quality specified in the table and for gamma radiation with the radiators indicated in the above table.</p> <p>The exposed area has a diameter of 50 mm. The attenuation of radiation by the test specimen is compared with lead of such a thickness that same attenuation of the dose rate is achieved in both cases.</p> <p>As detector, a scintillation dosimeter (scintillator 44 mm diameter, 15 mm height) is used. The measuring inaccuracy declared by the PTB has been subtracted.</p>		

VX 0050/1e

Specification					PCP RD 50™		
Physical and chemical properties							
6.2 Linear attenuation coefficients (μ) and tenth-value layers (TVL)							
Nuclide	Energy in MeV	μ in cm^{-1}	1 TVL in cm		Energy in MeV	Lead (Pb) Z=82	
						μ in cm^{-1}	1 TVL in cm
^{60}Co	1.25*	0.288	7.992		1.25*	0.650	3.544
^{137}Cs	0.662	0.473	4.866		0.662	1.174	1.961
^{18}F	0.511	0.621	3.710		0.511	1.637	1.406
	0.3	1.372	1.678		0.3	4.170	0.552
* arithmetic average of the 2 γ -emission lines 1.17 MeV and 1.33 MeV							
All data are calculated for narrow beam geometry (primary radiation)							
diagram						see annex	
<p>Reference (basic data of mass attenuation coefficients used for all elements)</p> <p>Ellery Storm, Harvey I. Israel: Photon Cross Sections from 0.001 to 100 MeV for Elements 1 through 100;</p> <p>Los Alamos Scientific Laboratory of the University of California; Report written: June 1967;</p> <p>Report distributed: November 15, 1967</p>							
7. Annex (diagrams, curves)							

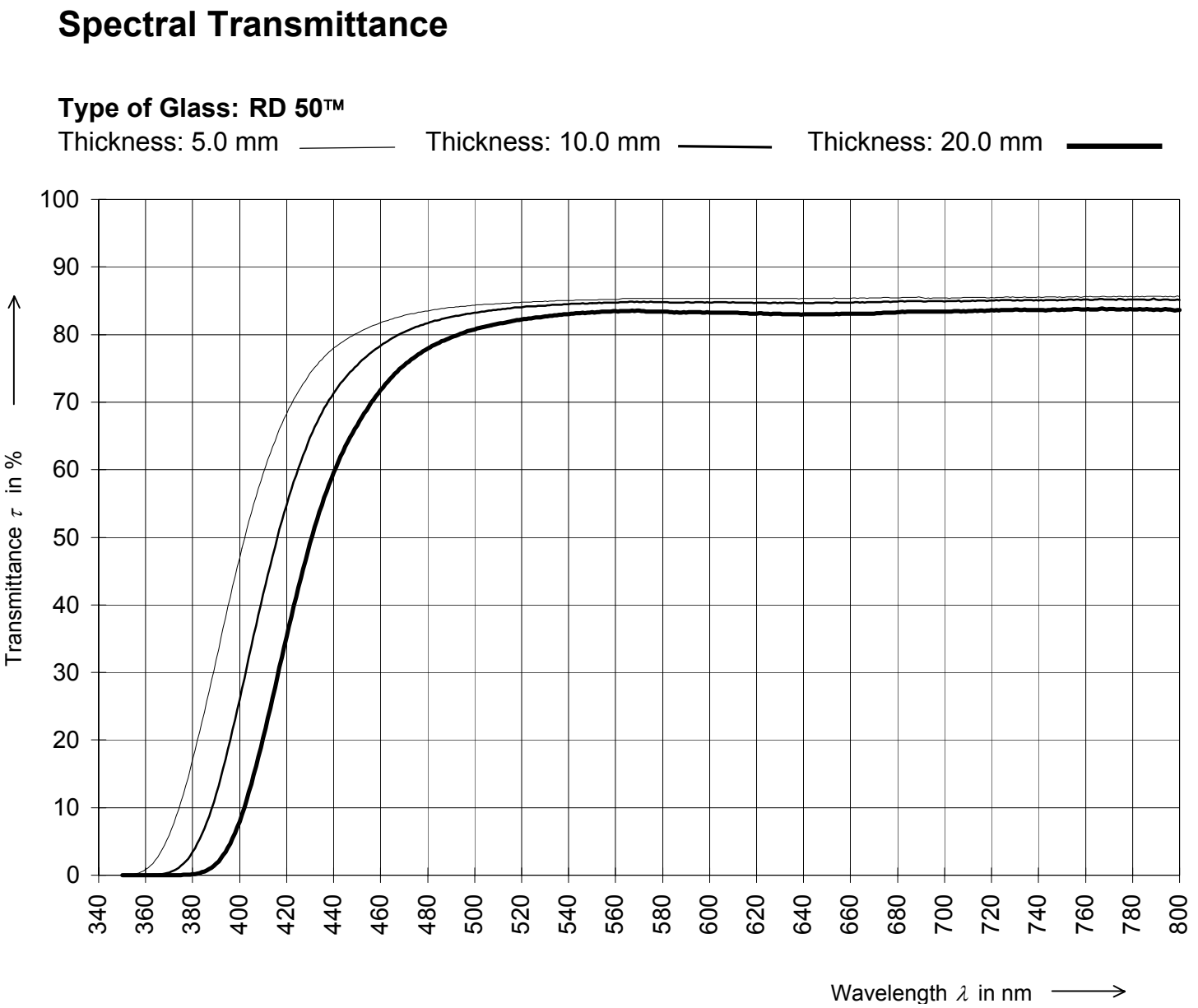
VX 0050/1e

Specification

Physical and chemical properties

PCP

RD 50™

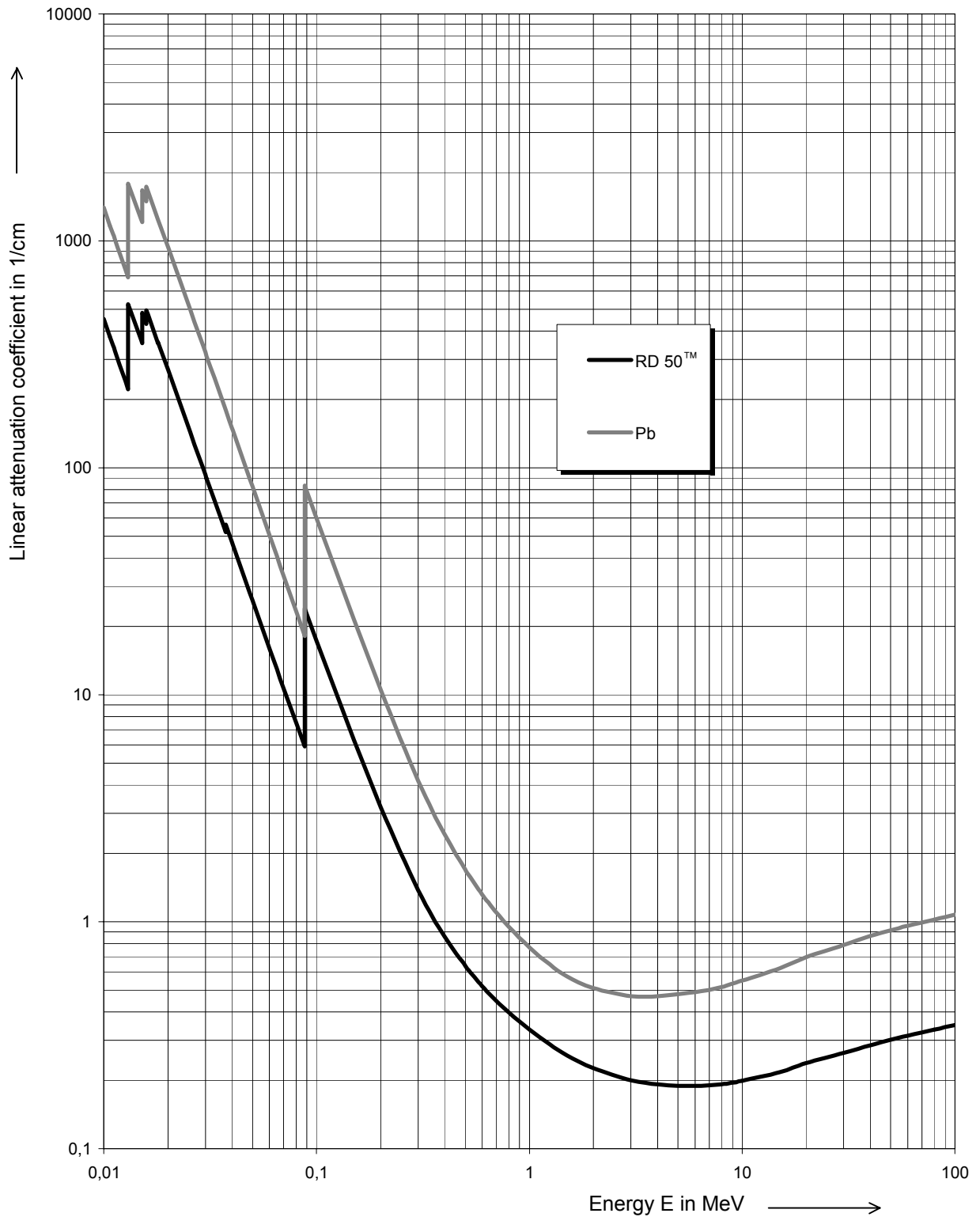


Specification

Physical and chemical properties

PCP
RD 50™

Linear attenuation coefficient



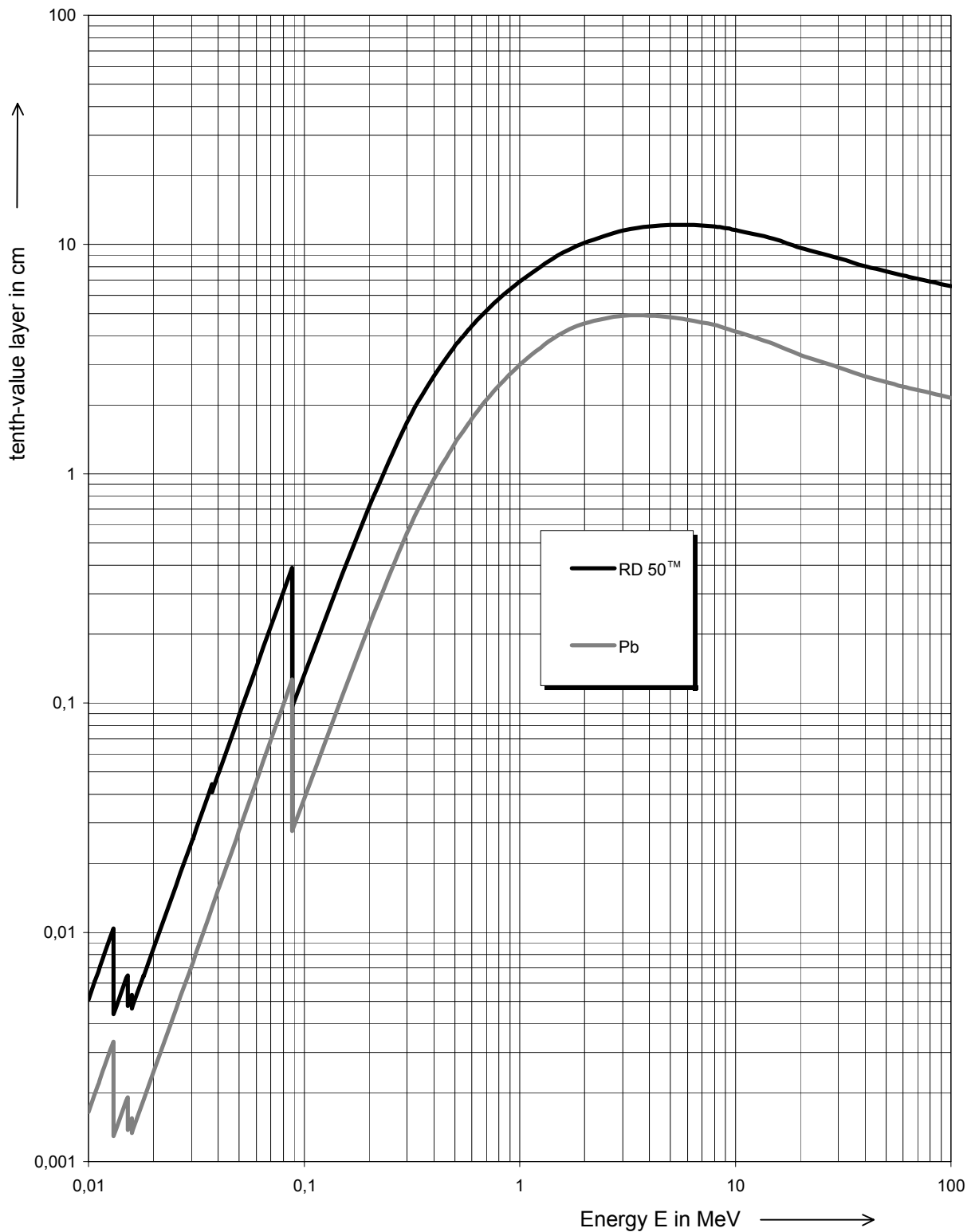
VX 0050/1e

Specification

Physical and chemical properties

PCP
RD 50™

Tenth-value layer



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